Residual permutation test for high-dimensional regression coefficient testing

Tengyao Wang

London School of Economics

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Kaiyue Wen Tsinghua University



Yuhao Wang Tsinghua University

Regression coefficient testing

We revisit one of the oldest problem in statistics: coefficient testing in linear model:

$$Y = X\beta + Zb + \epsilon$$

with $X \in \mathbb{R}^{n \times p}$ and $Z \in \mathbb{R}^n$ having fixed design and ϵ random noise in \mathbb{R}^n .

We want to test

 $H_0: b = 0$ versus $H_1: b \neq 0$.

Goal:

- develop test with non-asymptotic valid size
- understand difficulty of the problem in terms of the tail property of ϵ .





Assuming ϵ has i.i.d. Gaussian entries, Fisher (1921) proposed the ANOVA procedure

$$\frac{\operatorname{RSS}_X - \operatorname{RSS}_{X,Z}}{\operatorname{RSS}_{X,Z}} \sim F_{1,n-p-1}, \quad \text{under } H_0.$$

- The Gaussian error assumption can be relaxed to rotationally invariant or symmetric around zero noise (Hartigan, 1970; Meinshausen, 2015).
- Asymptotically, when $n \to \infty$ and p is fixed, the above test statistic is asymptotically χ_1^2 .

Size validity of ANOVA

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- *p*-value distribution is far from uniform
- Large spike around 0, causing poor size control, especially for small nominal size.
- Important to develop a distribution-free and finite-sample valid test!



- Permutation-based test can often achieve distribution-free size validity.
 - Freedman and Lane (1983) introduced a test based on permuting the regression residuals.
 - DiCiccio and Romano (2017) considered a permutation test using studentised partial correlations of Y and Z given X.
 - Toulis (2019) studied a test based on permuting residuals of Y against $({\cal Z}, {\cal X}).$
- However, these tests only have asymptotic size controls.
- ► Cyclic permutation test of Lei and Bickel (2021) achieves finite-sample validity, assuming $n/p \ge 1/\alpha 1$.



- We assume only that $\epsilon = (\epsilon_1, \dots, \epsilon_n)$ has **exchangeable** components.
- Given permutation matrices $P_1, \ldots, P_K \in \mathbb{R}^{n \times n}$
 - Let $\Pi_k \in \mathbb{R}^{n \times n}$ be the projection onto the orthogonal complement of the column span of $(X, P_k X)$ and write

$$\langle u, v \rangle_{\Pi_k} := u^\top \Pi_k v.$$

- Under
$$H_0$$
, for a fixed $k \in \{1, \ldots, K\}$,

$$\langle Z, Y \rangle_{\Pi_k} = \langle Z, \epsilon \rangle_{\Pi_k} \stackrel{\mathrm{d}}{=} \langle Z, P_k \epsilon \rangle_{\Pi_k} = \langle Z, P_k Y \rangle_{\Pi_k}$$

- Residuals of regression Y and $P_k Y$ against $(X, P_k X)$ should have be equally likely to correlate with Z under the null.
- Each P_k gives a 1-bit test of H_0 .

Combining the 1-bit tests into a level- α test



• Recall that under H_0 , the 1-bit test compares the magnitude of

$$a_k := \langle Z, Y \rangle_{\Pi_k} = \langle Z, \epsilon \rangle_{\Pi_k} \quad \text{and} \quad b_k := \langle Z, P_k Y \rangle_{\Pi_k} = \langle Z, P_k \epsilon \rangle_{\Pi_k}.$$

• To combine 1-bit tests from projections $P_0 = I_n, P_1, \ldots, P_K$, define

$$a^* := \min_{\ell \in \{1, \dots, K\}} a_\ell \quad \text{and} \quad b^*_k := \min_{\ell \in \{1, \dots, K\}} \langle Z, P_k \epsilon \rangle_{\Pi_\ell}.$$



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• If P_0, \ldots, P_K form a group, then

$$\phi^* = \frac{1}{K+1} \left(1 + \sum_{k=1}^K \mathbb{1}\{a^* \le b_k^*\} \right)$$

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• Unfortunately, ϕ^* is not computable from data: $\langle Z, P_k \epsilon \rangle_{\Pi_\ell} \neq \langle Z, P_k Y \rangle_{\Pi_\ell}$.

An admissible test with valid size control



▶ Instead of ϕ^* , we use

$$\phi = \frac{1}{K+1} \left(1 + \sum_{k=1}^{K} \mathbb{1} \{ a^* \le b_k \} \right),$$

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- Computational complexity: same as running K OLS regressions, so $O(Kp^2n)$.
- ► In addition to using Euclidean inner products, we can also construct test using any function $T(\Pi_k Z, \Pi_k Y)$.



 $\blacktriangleright \phi$ has finite-sample size validity under weak assumptions.

Theorem. Assume $Y = X\beta + Zb + \epsilon$ with ϵ having exchangeable components and p < n/2. If $\{P_0, P_1, \dots, P_K\}$ forms a group, then ϕ defined above satisfies

$$\mathbb{P}(\phi \le \alpha) \le \frac{\lfloor \alpha(K+1) \rfloor}{K+1} \le \alpha,$$

for all $\alpha \in [0, 1]$.



- Since ϵ is exchangeable, it is invariant under group action of $\mathcal{P} = \{P_1, \dots, P_K\}.$
- The set $\{\Pi_1, \ldots, \Pi_K\}$ is also invariant under action of the group \mathcal{P} .
- Hence the test statistics a^*, b_1^*, \dots, b_K^* are invariant under group action of \mathcal{P} , in particular, rank of a^* is uniformly distributed in $\{1, \dots, K\}$.



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(Assumption A3) We assume that ε = (ε₁,..., ε_n) have i.i.d. components distributed from a centred distribution P_ε, and that

$$Z = X\gamma + e$$

with $e = (e_1, \ldots, e_n)^{\top}$ independent from ϵ with i.i.d. components distributed from a centred distribution \mathbb{P}_e .

• (Assumption A4) Assume additionally that the permutation matrices P_1, \ldots, P_K satisfies $\operatorname{tr}(P_k) = 0$ and $|\operatorname{tr}(\Pi_0 P_k)| \leq \sqrt{2p}K$.



- Assumption (A4) is relatively mild. It can be shown that a group P_0, P_1, \ldots, P_K satisfying (A4) always exists and we can find a random algorithm that has a success probability of 1 1/K in finding such a permutation group in each iteration.
- Assumption (A3) appears more stringent. The nodewise regression structural assumption of Z is similar to the assumption in debiased Lasso.
- We can relax the linear structural assumption on Z to allow for nonlinearity.



• We are interested in how the minimal testable signal strength b is related to the tail heaviness of e and ϵ .

Theorem. Suppose $Y = X\beta + Zb + \epsilon$ where ϵ and Z satisfies Assumption (A3) and

 $0 < \mathbb{E} |e_1|^2 < \infty \quad \text{and} \quad 0 < \mathbb{E} |\epsilon_1|^{1+t} < \infty$

for some $t \in [0, 1]$. Assume P_0, P_1, \ldots, P_K satisfies Assumption (A4). In the asymptotic regime where b and p vary with n in such a way that n > (3 + m)p for some constant m > 0 and

$$|b| \gtrsim n^{-t/(1+t)}$$
 if $t < 1$ or $|b| \gg n^{-1/2}$ if $t = 1$,

we have $\lim_{n\to\infty} \mathbb{P}(\phi > \frac{1}{K+1}) = 0.$

Sketch of proof for power analysis



We need to show that

$$a_{\ell} = \langle Z, Y \rangle_{\Pi_{\ell}} = \langle e, be + \epsilon \rangle_{\Pi_{\ell}}$$

dominates

$$b_k = \langle Z, P_k Y \rangle_{\Pi_k} = \langle e, bP_k e + P_k \epsilon \rangle_{\Pi_k}$$

for all $\ell, k \in [K]$.



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• It suffices to show that for al $k \in [K]$

$$\langle e, \epsilon \rangle_{\Pi_k} = o_p(bn) \langle e, P_k \epsilon \rangle_{\Pi_k} = o_p(bn) \langle e, e \rangle_{\Pi_k} = n - 2p + o_p(n) \langle e, P_k e \rangle_{\Pi_k} \le p + \sqrt{2p}K + o_p(n)$$

The key step is to analyse the correlation of e and ε on the projection space of Π_k.



- Let \mathcal{D}_t be the class of distributions with *t*-th order moment bounded between [1, 2].
- ▶ If $\mathbb{P}_e \in \mathcal{D}_2$ and $\mathbb{P}_\epsilon \in \mathcal{D}_{1+t}$, then a signal strength of $|b| \gtrsim n^{-t/(1+t)}$ is sufficient for RPT to be asymptotically powerful.
- The following result shows that this signal strength requirement is essentially optimal.

Theorem. Fix $t \in (0, 1]$. Suppose $Y = X\beta + Zb + \epsilon$ where ϵ and Z satisfies Assumption (A3). For any $\eta \in (0, 1)$, there exists $c_{\eta} > 0$ depending only on η such that for any fixed design X,

$$\inf_{\substack{\text{test }\varphi \\ \mathbb{P}_{e} \in \mathcal{D}_{1} \\ \mathbb{P}_{e} \in \mathcal{D}_{1} \\ \beta, \gamma \in \mathbb{R}^{p}}} \sup_{\mathbb{P}_{e} \in \mathcal{D}_{1} \\ \mathbb{P}_{e} \in \mathcal{D}_{1} \\ \beta, \gamma \in \mathbb{R}^{p}}} \sup_{\mathbb{P}_{e} \in \mathcal{D}_{1} \\ \beta, \gamma \in \mathbb{R}^{p}}} \sup_{\substack{b \ge c_{\eta} n^{-t/(1+t)} \\ \beta \in \mathcal{D}_{1} \\ \beta, \gamma \in \mathbb{R}^{p}}} \mathbb{P}_{b}(\varphi = 0) \Big\} \ge 1 - \eta.$$

Numerical simulations: size control

- Empirical size under the null for various design and noise distributions.
- We compare against DiCiccio and Romano (2017), Freedman and Lane (1983) and CRT of Candès et al. (2018).

				RP'	Гпи	R PT		DR		FI		CRT	
		v				101 0 501							
n	p	X	noise	1%	0.5%	1%	0.5%	1%	0.5%	1%	0.5%	1%	0.5%
300	100	\mathcal{G}	${\mathcal G}$	0	0	0	0	0.98	0.5	0.99	0.52	0	0
300	100	\mathcal{G}	t_1	0.51	0.12	0.24	0	0.88	0.43	1.28	0.81	1.89	1.66
300	100	\mathcal{G}	t_2	0.14	0.02	0.04	0	0.67	0.3	1.23	0.64	0.53	0.37
300	100	t_1	\mathcal{G}	0	0	0	0	3.33	2.22	1.01	0.51	0	0
300	100	t_1	t_1	0.01	0	0	0	1.28	0.66	1.21	0.72	0.33	0.29
300	100	t_1	t_2	0	0	0	0	2.54	1.49	1.09	0.55	0	0
600	100	$\bar{\mathcal{G}}$	$\bar{\mathcal{G}}$	0.21	0.07	0.01	0	0.95	0.5	0.95	0.47	0	0
600	100	\mathcal{G}	t_1	0.73	0.43	0.48	0.28	0.92	0.48	1.09	0.59	1.68	1.49
600	100	\mathcal{G}	t_2	0.61	0.33	0.20	0.12	0.68	0.33	1.09	0.58	0.61	0.45
600	100	t_1	$\overline{\mathcal{G}}$	0.23	0.07	0.01	0	3.95	2.65	0.93	0.47	0	0
600	100	t_1^-	t_1	0.13	0.03	0	0	1.37	0.72	1.04	0.54	0.25	0.22
600	100	t_1^-	t_2^-	0.10	0.03	0	0	3.33	2.04	1.05	0.52	0.01	0
600	200	Ĝ	$\bar{\mathcal{G}}$	0	0	0	0	1.04	0.53	1.02	0.53	0	0
600	200	\mathcal{G}	t_1	0.46	0.34	0.26	0.17	0.89	0.44	1.18	0.75	1.5	1.3
600	200	\mathcal{G}	t_2	0.12	0.10	0.04	0.03	0.68	0.33	1.2	0.67	0.49	0.34
600	200	t_1	$\bar{\mathcal{G}}$	0	0	0	0	3.45	2.28	0.98	0.49	0	0
600	200	t_1^-	t_1	0.01	0	0	0	1.25	0.63	1.13	0.63	0.27	0.23
600	200	t_1	t_2	0	0	0	0	2.71	1.64	1.01	0.51	0	0

Numerical simulations: power curves



Empirical power curves against signal size b for various design and noise distributions.





(a) Gaussian design, Gaussian noise



(c) t_1 design, Gaussian noise

(b) Gaussian design, t_1 noise



(d) t_1 design, t_1 noise



▶ Instead of a linear model of Z on X and $\epsilon \perp \!\!\!\perp e$, we allow

- Z to depend nonlinearly on $X: Z_i = f(X_i\gamma) + e_i$, where $f: t \mapsto 1/(1 + e^{-t})$ is the sigmoid function.
- e and ϵ to be dependent: e has independent t_1 entries, and ϵ has either t_1 and $2t_1$ entries dependent on the sign of entries of e.

Numerical simulations: misspecification





(a) independent noise, linear relation



(c) independent noise, nonlinear relation



(b) dependent noise, linear relation



(d) dependent noise, nonlinear relation



- We propose a finite-sample valid permutation-based test for a single regression coefficient in a high-dimensional setting
- Key idea: compute projected correlation on the subspace orthogonal to both the original and permuted design matrix.
- Optimal power result showing minimal detectable signal b in terms of tail-heaviness of the noise under suitable modelling assumption of design.
- R Package available on github.com/wangtengyao/ResPerm.

Main reference:

Wen, K., Wang, T. and Wang, Y. (2022) Residual permutation test for high-dimensional regression coefficient testing. *Preprint*, arxiv:2211.16182. Thank you!



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